## FORM HDP-1449 (Based on Form PTO-1449)

## PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION

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Sheet 1 of 1

ATTORNEY DOCKET NO.	SERIAL NO.	
6340-000034		
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U.S. PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1,5		2002-0067840	6/2002	Kobayashi		
2.	CAL)	2003-0053645-A1	3/2003	Kobayashi		

FORE	FOREIGN PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	No
1.5	1	6-22395	1/1994	Japan		Abstract	

OTHE	OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)					
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Sheet 1 of 1

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August 21, 2003	2644

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FORE	IGN PATEN	T DOCUMENTS					
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	No
. 4	THE D	JP 59-139800	8/1984	Japan		Abstract	

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